

## Supplementary Information

### X-ray Photoelectron Spectroscopy (XPS) Result Analysis

Note: Si 2s and Si 2p peaks were determined as contaminants and omitted from the analysis as they are detected due to the glass slide on which the samples were mounted.

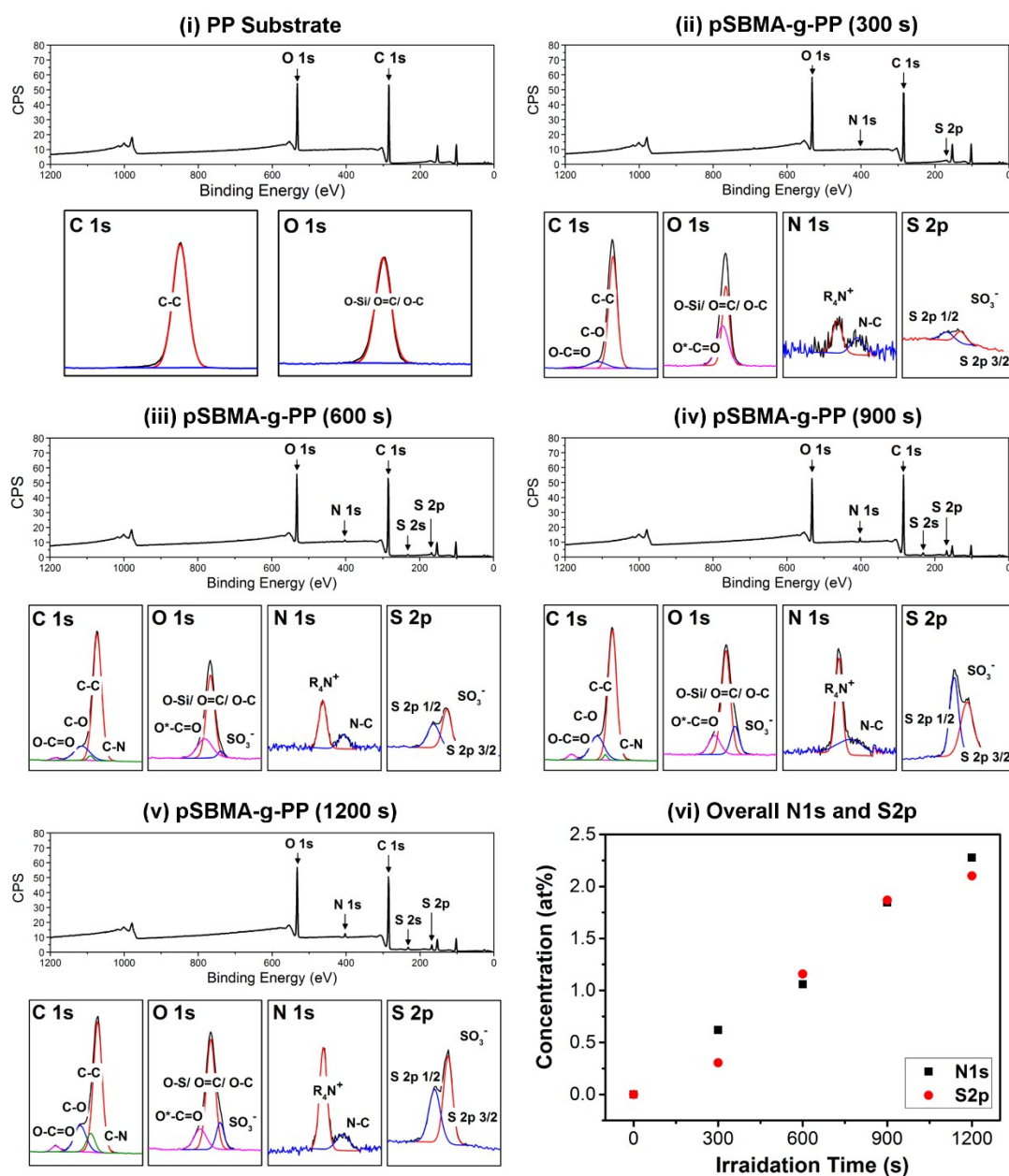


Figure S1. XPS results of the PP substrate (i), and pSBMA-grafted samples irradiated for (ii) 300 s, (iii) 600 s, (iv) 900 s and (v) 1200 s. Sub-figures show the survey scan with labelled elemental peaks; and the corresponding region scans detailing the identified chemical states of the respective elements. The detected N 1s and S 2p concentrations on each sample are compared in (vi).